

Description

The VSM75N20 advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in automotive applications and a wide variety of other applications.

General Features

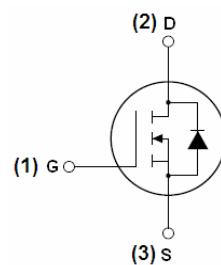
- $V_{DSS} = 200V, I_D = 75A$
- $R_{DS(ON)} < 20m\Omega @ V_{GS}=10V$
- Good stability and uniformity with high E_{AS}
- Special process technology for high ESD capability
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

Application

- Automotive applications
- Hard switched and high frequency circuits
- Uninterruptible power supply



TO-220C



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM75N20-TC	VSM75N20	TO-220C	-	-	-

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	200	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	75	A
Drain Current-Continuous($T_c=100^\circ C$)	$I_D (100^\circ C)$	53	A
Pulsed Drain Current	I_{DM}	300	A
Maximum Power Dissipation	P_D	360	W
Derating factor		2.4	W/ $^\circ C$
Single pulse avalanche energy <small>(Note 3)</small>	E_{AS}	1512	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 1)	R _{θJC}	0.42	°C/W
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Electrical Characteristics (T_c=25°C unless otherwise noted)

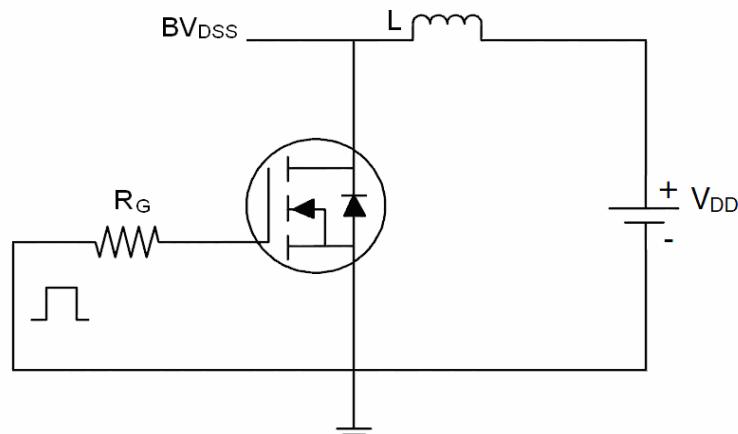
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	200	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =200V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±200	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2.5	3.5	4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =40A	-	17.8	20	mΩ
Forward Transconductance	g _{fS}	V _{DS} =50V, I _D =40A		79	-	S
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =50V, V _{GS} =0V, F=1.0MHz	-	6990	-	PF
Output Capacitance	C _{oss}		-	950	-	PF
Reverse Transfer Capacitance	C _{rss}		-	700	-	PF
Switching Characteristics						
Turn-on Delay Time	t _{d(on)}	V _{DD} =100V, I _D =40A, V _{GS} =10V, R _G =2.7Ω	-	17	-	nS
Turn-on Rise Time	t _r		-	18	-	nS
Turn-Off Delay Time	t _{d(off)}		-	56	-	nS
Turn-Off Fall Time	t _f		-	22	-	nS
Total Gate Charge	Q _g	ID=40A, VDD=100V, VGS=10V	-	140	-	nC
Gate-Source Charge	Q _{gs}		-	40	-	nC
Gate-Drain Charge	Q _{gd}		-	45	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =75A	-	-	1.2	V
Reverse Recovery Time	t _{rr}	T _J = 25°C, IF = 40A di/dt = 100A/μs ^(Note2)	-	136	-	nS
Reverse Recovery Charge	Q _{rr}		-	458	-	nC

Notes:

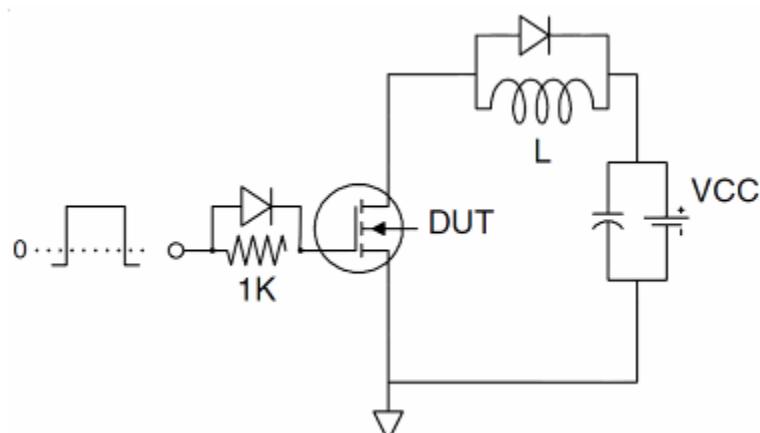
1. Surface Mounted on FR4 Board, t ≤ 10 sec.
2. Pulse Test: Pulse Width ≤ 400μs, Duty Cycle ≤ 2%.
3. EAS condition: T_j=25°C, V_{DD}=50V, V_G=10V, L=1mH, R_g=25Ω, I_{AS}=55A
4. I_{SD}≤125A, di/dt≤260A/μs, V_{DD}≤V_{(BR)DSS}, T_j ≤175°C

Test Circuit

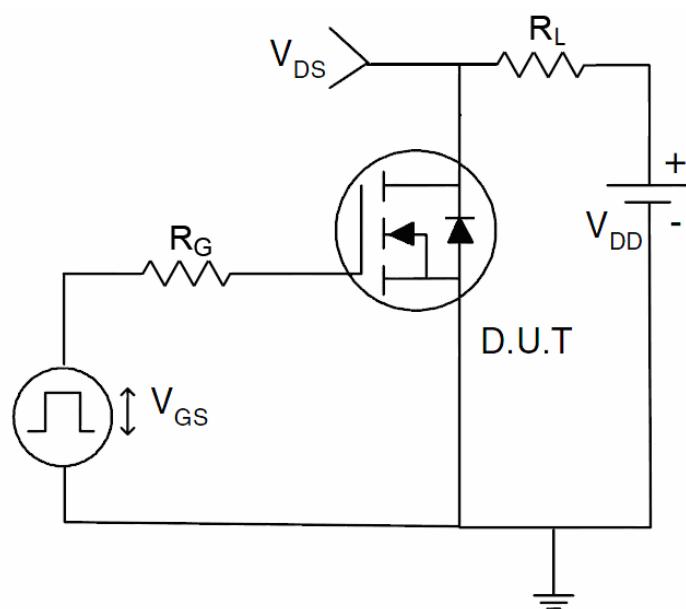
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics

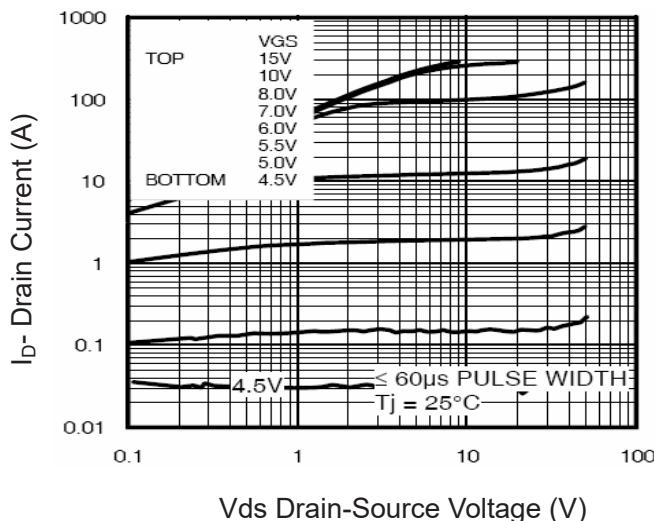


Figure 1 Output Characteristics

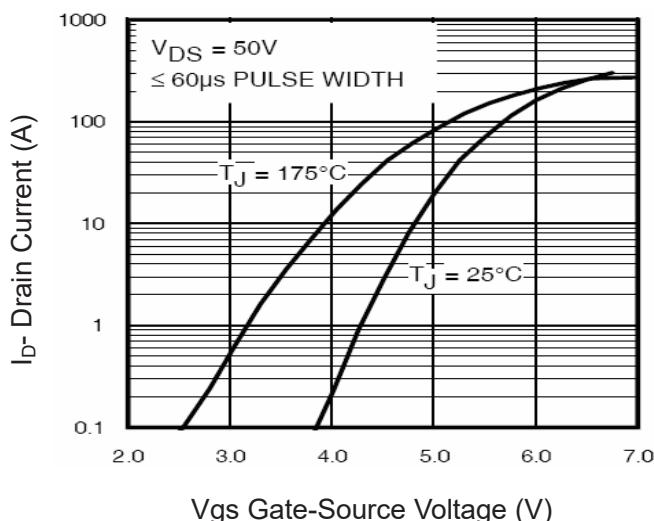


Figure 2 Transfer Characteristics

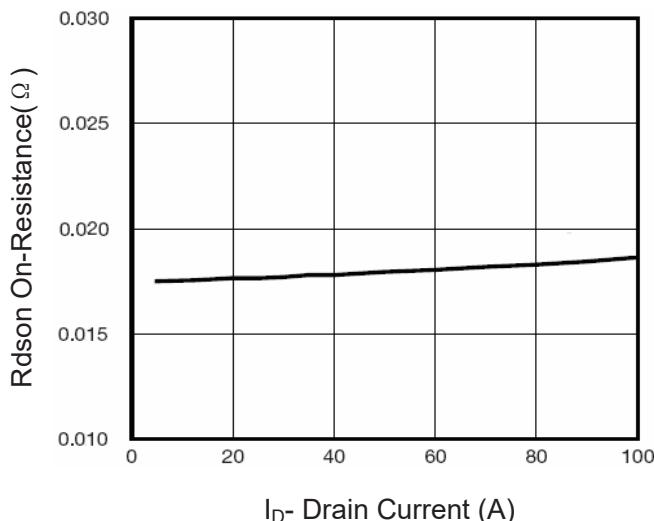


Figure 3 Rdson- Drain Current

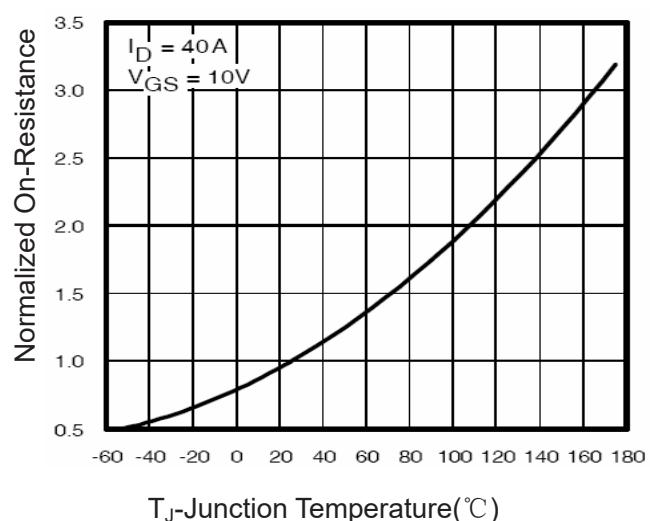


Figure 4 Rdson-JunctionTemperature

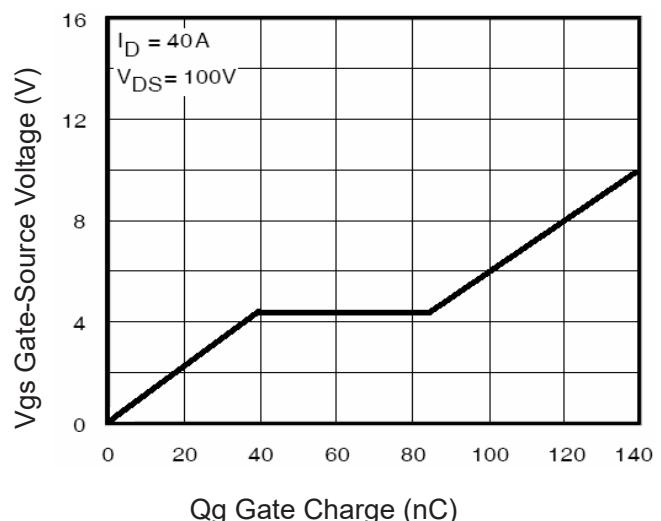


Figure 5 Gate Charge

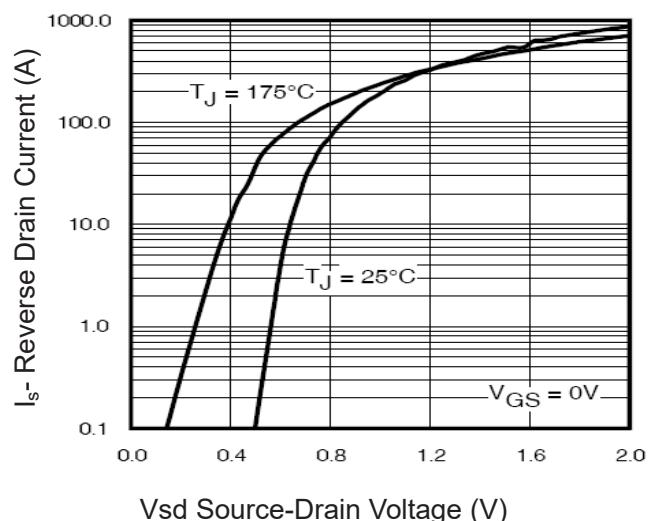
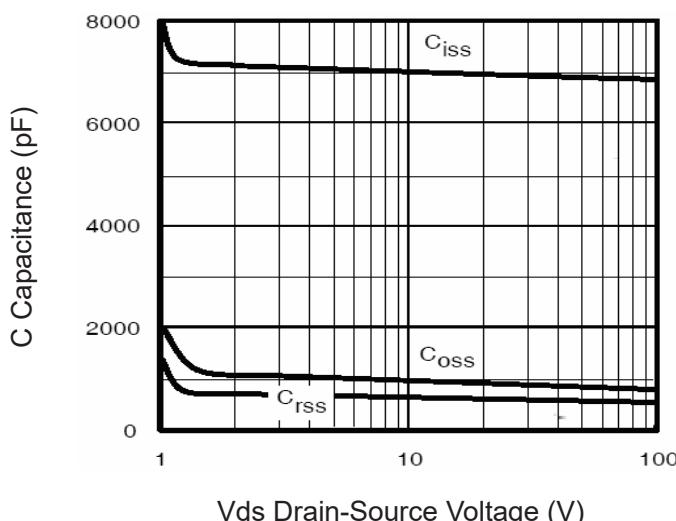
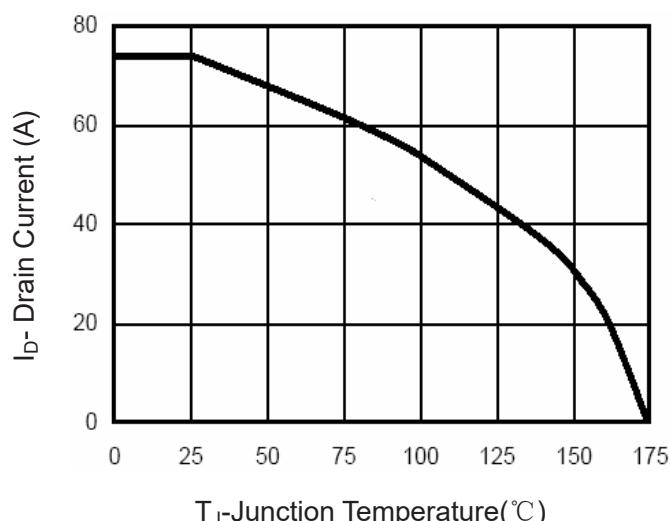
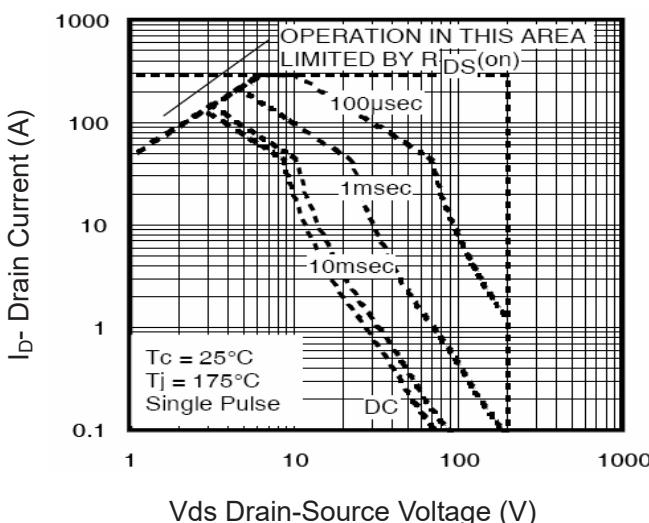
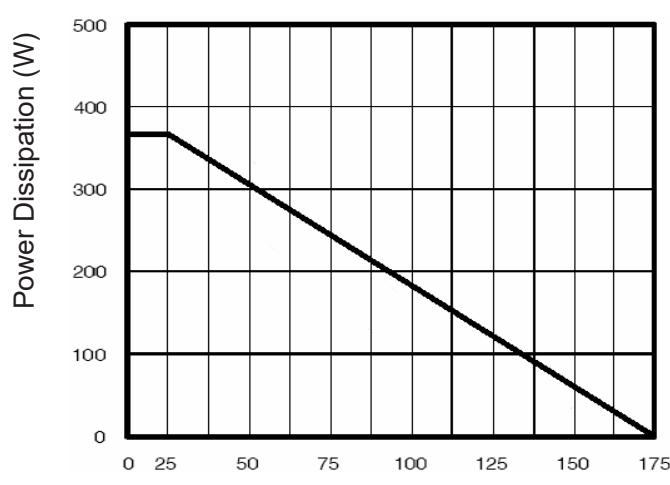
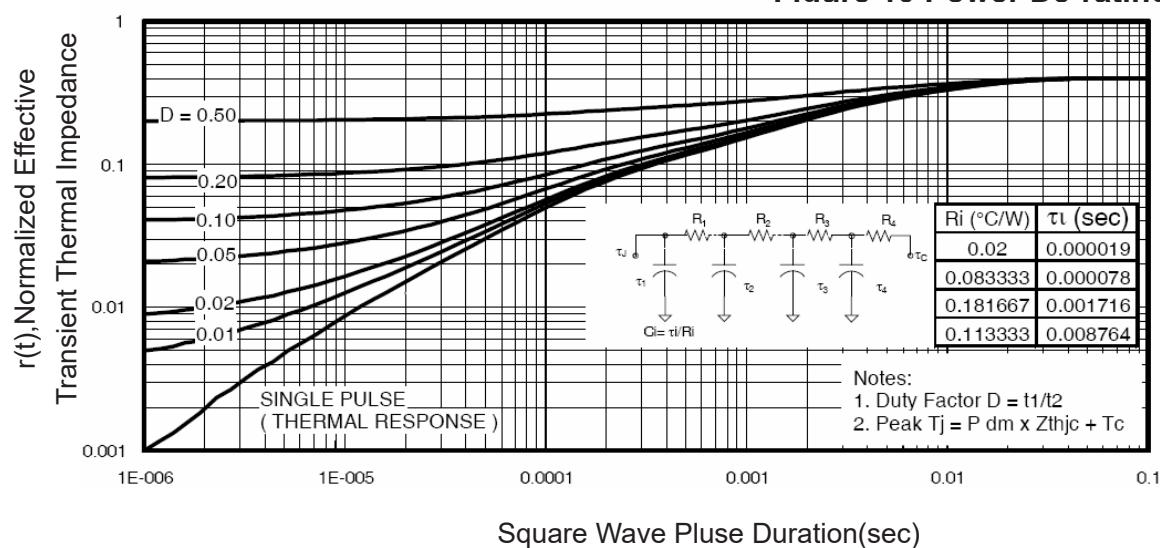


Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 ID Current Derating vs Junction Temperature

Figure 8 Safe Operation Area

Figure 10 Power De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance